

STP120NF04

N-channel 40V - 0.0047Ω - 120A TO-220 STripFET™ II MOSFET

General features

Туре	v_{DSS}	R _{DS(on)}	I _D	Pw
STP120NF04	40V	<0.0050Ω	120A	300W

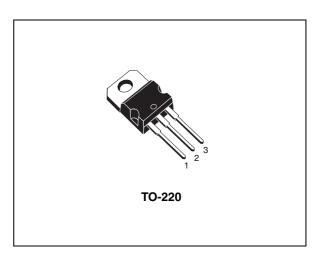
- Standard threshold drive
- 100% avalanche tested

Description

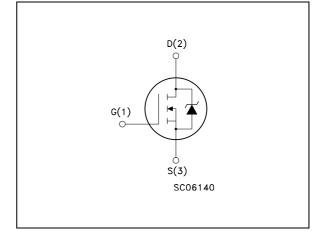
This MOSFET is the latest development of STMicroelectronics unique "Single Feature Size™" strip-based process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

Applications

Switching application



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STP120NF04	P120NF04	TO-220	Tube

October 2006

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1

Electrical ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	40	V
V _{GS}	Gate-source voltage	± 20	V
I _D ⁽¹⁾	Drain current (continuous) at $T_{C} = 25^{\circ}C$	120	А
I _D	Drain current (continuous) at $T_C = 100^{\circ}C$	120	А
I _{DM} ⁽²⁾	Drain current (pulsed)	480	А
P _{TOT}	Total dissipation at $T_C = 25^{\circ}C$	300	W
	Derating factor	2	W/°C
dv/dt ⁽³⁾	Peak diode recovery voltage slope	6	V/ns
E _{AS} ⁽⁴⁾	Single pulse avalanche energy	1.2	J
Т _Ј T _{stg}	Operating junction temperature Storage temperature	-55 to 175	°C

1. Current Limited by Package

2. Pulse width limited by safe operating area

3. $I_{SD} \leq 20A$, di/dt $\leq 300A/\mu s$, $V_{DD} \leq V_{(BR)DSS}$, $T_j \leq T_{JMAX}$.

4. Starting $T_j = 25^{\circ}C$, $I_d = 60A$, $V_{DD}=30 V$

Table 2. Thermal data

R _{thj-case}	Thermal resistance junction-case Max	0.5	°C/W
Rthj-pcb	Thermal resistance junction-pcb Max	see Figure 14. on page 8	°C/W
R _{thj-a}	Thermal resistance junction-ambient (free air) Max	62.5	°C/W
Τ _Ι	Maximum lead temperature for soldering purpose	300	°C



2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_{D} = 250 \ \mu A, \ V_{GS} = 0$	40			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = Max Rating V _{DS} = Max Rating, T _C = 125 °C			1 10	μΑ μΑ
I _{GSS}	Gate body leakage current (V _{DS} = 0)	$V_{GS} = \pm 20V$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.8		4.5	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10V, I _D = 50 A		0.0047	0.0050	Ω

Table 3. On/off states

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 _{fs} ⁽¹⁾	Forward transconductance	V _{DS} =15V, I _D = 50A		150		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} =25V, f=1 MHz, V _{GS} =0		5100 1300 160		pF pF pF
t _{d(on)} t _r	Turn-on delay time rise time	$V_{DD} = 20 \text{ V}, \text{ I}_{D} = 60 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 18)		35 220		ns ns
t _{d(off)} t _f	Turn-off delay time fall time	$V_{DD} = 20 \text{ V}, \text{ I}_{D} = 60 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 18)		80 50		ns ns
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V _{DD} =32V, I _D = 120A V _{GS} =10V (see Figure 19)		110 35 35	150	nC nC nC

1. Pulsed: pulse duration=300µs, duty cycle 1.5%



Symbol	Parameter	Test conditions	Min	Тур.	Max	Unit
I _{SD}	Source-drain current				120	А
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				480	А
$V_{SD}^{(2)}$	Forward on voltage	I _{SD} =120A, V _{GS} =0			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} =120A, di/dt = 100A/μs, V _{DD} =20V, Tj=150°C (see Figure 20)		75 185 5		ns nC A

 Table 5.
 Source drain diode

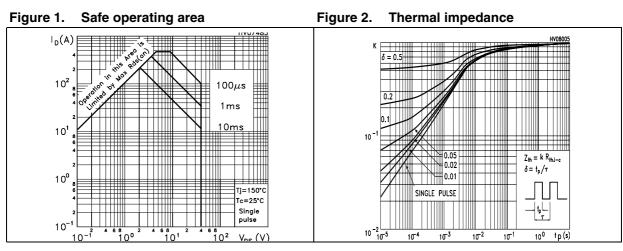
1. Pulse width limited by safe operating area

2. Pulsed: pulse duration=300µs, duty cycle 1.5%

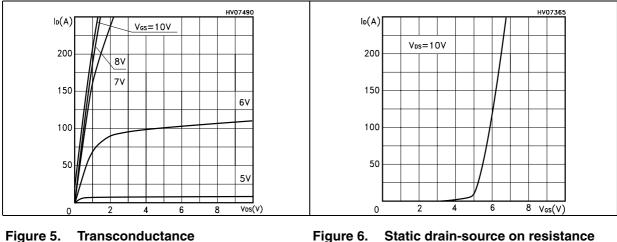


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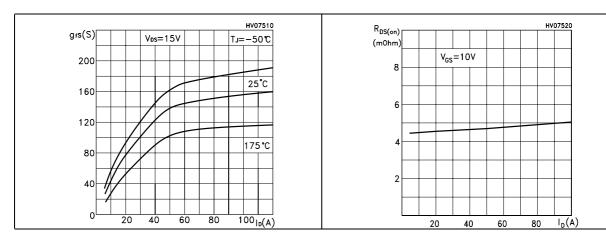
Electrical characteristics (curves) 2.1



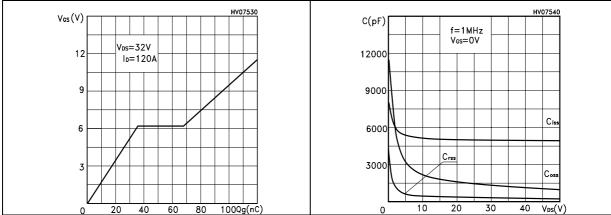












Gate charge vs gate-source voltage Figure 8. Figure 7. Capacitance variation

Figure 9. Normalized gate threshold voltage vs temperature

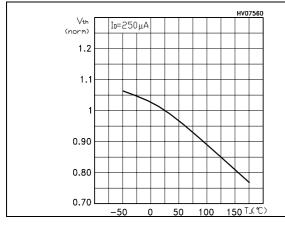


Figure 11. Normalized on resistance vs temperature

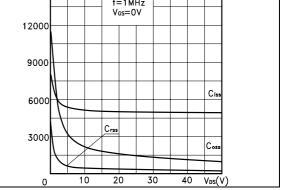


Figure 10. Normalized B_{VDSS} vs temperature

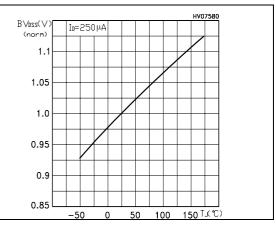


Figure 12. Source-drain diode forward characteristics

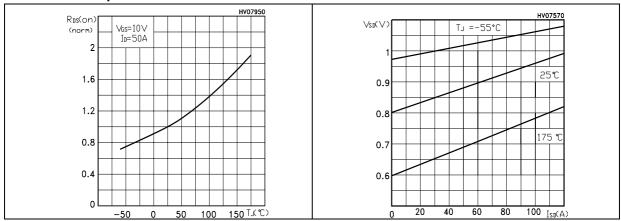
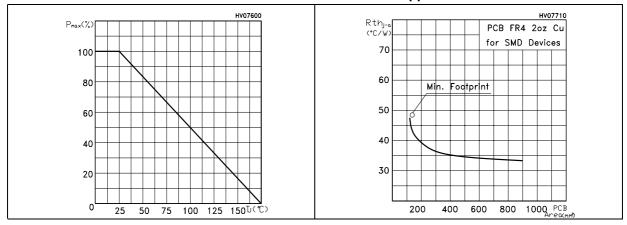


Figure 13. Power derating vs Tc



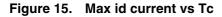


Figure 16. Max power dissipation vs PCB copper area

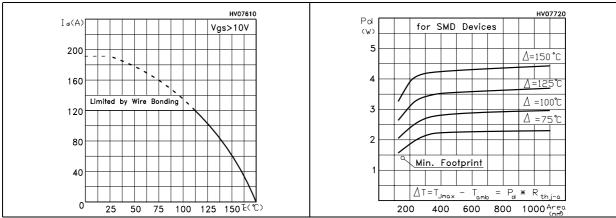
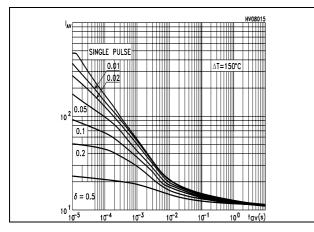


Figure 14. Thermal resistance Rthj-a vs PCB copper area

Figure 17. Allowable lav vs time in avalanche



The previous curve gives the safe operating area for unclamped inductive loads, single pulse or repetitive, under the following conditions:

P_{D(AVE)} =0.5*(1.3*BV_{DSS} *I_{AV})

 $E_{AS(AR)} = P_{D(AVE)} * t_{AV}$

Where:

IAV is the allowable current in avalanche

P_{D(AVE)} is the average power dissipation in avalanche (single pulse)

 $t_{\mbox{\scriptsize AV}}$ is the time in avalanche

To derate above 25 °C, at fixed I_{AV} the following equation must be applied:

 $I_{AV} = 2 * (T_{jmax} - T_{CASE}) / (1.3 * BV_{DSS} * Z_{th})$ Where:

 Z_{th} = K * R_{th} is the value coming from Normalized Thermal Response at fixed pulse width equal to T_{AV}



3 **Test circuit**

Figure 18. Switching times test circuit for resistive load

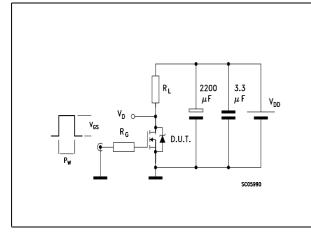
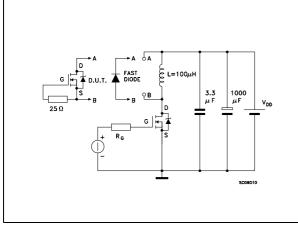


Figure 20. Test circuit for inductive load switching and diode recovery times





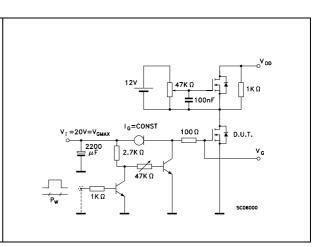


Figure 21. Unclamped Inductive load test circuit

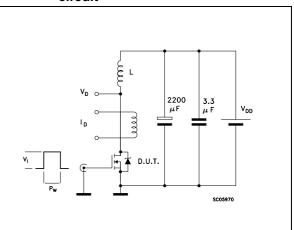


Figure 23. Switching time waveform

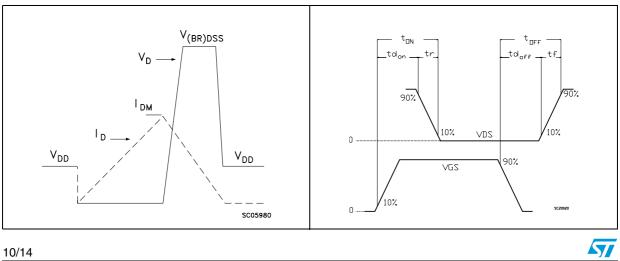


Figure 19. Gate charge test circuit

4 Package mechanical data

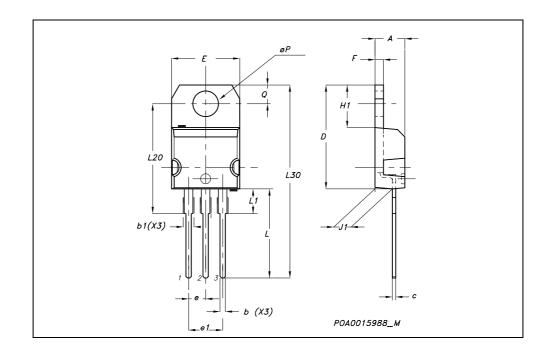
In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com



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DIM.		mm.		inch		
DIN.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.
А	4.40		4.60	0.173		0.181
b	0.61		0.88	0.024		0.034
b1	1.15		1.70	0.045		0.066
С	0.49		0.70	0.019		0.027
D	15.25		15.75	0.60		0.620
Е	10		10.40	0.393		0.409
е	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
F	1.23		1.32	0.048		0.052
H1	6.20		6.60	0.244		0.256
J1	2.40		2.72	0.094		0.107
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L20		16.40			0.645	
L30		28.90			1.137	
øР	3.75		3.85	0.147		0.151
Q	2.65		2.95	0.104		0.116

TO-220 MECHANICAL DATA



5 Revision history

Table 6.	Revision	history
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Date	Revision	Changes
28-Feb-2005	1	First release.
02-Oct-2006	2	New template, no content change



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